

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/709,949	HEMMETT, JEFFREY E.	
Examiner Russell Frejd		Art Unit 2128	Page 1 of 2	

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,096,174	08-2006	Beattie et al.	703/14
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	YUAN et al., F. Efficient Transient Analysis of Nonlinear Circuits Using Volterra Series and Piecewise Constant Interpolation, 2001 IEEE International Symposium on Circuits and Systems, Vol. 3, May 2001, pp. 819-22.
	V	ROVNYAK et al., S. Predicting Future Behavior of Transient Events Rapidly Enough to Evaluate Remedial Control Options in Real-Time, IEEE Transactions on Power Systems, Vol. 10, No. 3, August 1995, pp. 1195-1203.
	W	LIU et al., C.-W. New Methods for Computing Power System Dynamic Response for Real-Time Transient Stability Prediction, IEEE Transactions on Circuits and Systems-1:Fundamental Theory and Applications, Vol. 47, No. 3, March 2000, pp. 324-37.
	X	TIWARI et al., A.P. Spatial Control of a Large PHWR by Piecewise Constant Periodic Output Feedback, IEEE Transactions on Nuclear Science, Vol. 47, No. 2, April 2000, pp. 389-402.

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

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	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	CHEN et al., H.-J., Analytical Transient Solution for Short-Channel CMOS Devices Using a Pseudo Piecewise Constant Approach, IEEE, 42nd Midwest Symposium on Circuits and Systems, Vol. 1, August 1999, pp. 317-20.
	V	
	W	
	X	

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 Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.